

FORM PTO-1449	ATTY. DKT NO.	1-103-CONS	SER. NO.
	APPLICANT	MAMITSU et al.	
	FILING DATE	Nov. 4, 2003	GROUP

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>RP</i>	5,708,299	Jan. 13, 1998	Teramae et al		
<i>RP</i>	6,072,240	June 6, 2000	Kimura et al		
<i>RP</i>	5,248,853	Sep. 28, 1993	Ishikawa et al		
<i>RP</i>	5,801,445	Sep. 1, 1998	Ishihara et al		
<i>RP</i>	5,229,646	Jul. 20, 1993	Tsumura		
<i>RP</i>	4,558,345	Dec. 10, 1985	Dwyer et al		
<i>RP</i>	4,546,374	Oct. 8, 1985	Olsen et al		
<i>RP</i>	4,984,061	Jan. 8, 1991	Matsumoto		
<i>RP</i>	5,481,137	Jan 2, 1996	Harada et al.		
<i>RP</i>	4,827,082	May 2, 1989	Horiuchi et al		
<i>RP</i>	4,538,170	Aug. 27, 1985	Yerman		

FOREIGN PATENT DOCUMENTS

TRANSLATION									
	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO	
<i>RP</i>	EP0660396	12/24/93	Europe						
<i>RP</i>	EP0450980	4/05/91	Europe						
<i>RP</i>	6-291223	10/94	JAPAN						
<i>RP</i>	3-20067	01/91	JAPAN						
<i>RP</i>	2146174	11/85	GB						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

		Takamura, "Electronic Technology", pp. 56-59 (1999-5).
<i>RP</i>		Johnson et al., "Silicon Precipitate Nodule-Induced Failures of MOSFETS", ISTFA '91 (Nov. 11-15, 1991), pp. 161-165.
EXAMINER	<i>RP</i>	DATE CONSIDERED 9/3/04

FORM PTO-1449	ATTY. DKT NO.	1-103-CON5	SER. NO.
	APPLICANT	MAMITSU et al.	
	FILING DATE	Nov. 04, 2003	GROUP

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>PS</i>		4,646,129	Feb. 24, 1987	Yerman et al		
<i>PS</i>		4,141,030	Feb. 20, 1979	Eisele et al		
<i>PS</i>		6,448,645	Sep. 10, 2002	Kimura		
<i>PS</i>		6,538,308	Mar. 25, 2003	Nakase		
<i>PS</i>		6,380,622	Apr. 30, 2002	Hirai		
<i>PS</i>		09/675,209	Filed Sept. 29, 2000	Suzuki		
<i>PS</i>		5,221,851	Jun. 22, 1993	Gobrecht et al.		

FOREIGN PATENT DOCUMENTS

TRANSLATION

		DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
<i>PS</i>		4-249353	9/92	JAPAN					
<i>PS</i>		11-260979	09/99	JAPAN					
<i>PS</i>		4-27145	01/92	JAPAN					
<i>PS</i>		9-148492	06/97	JAPAN					
<i>PS</i>		4-12555	01/92	JAPAN					
<i>PS</i>		4-103150	04/92	JAPAN					
<i>PS</i>		60-137042	07/85	JAPAN					
<i>PS</i>		5-109919	04/93	JAPAN					
<i>PS</i>		61-166051	07/86	JAPAN					
<i>PS</i>		2-117157	05/90	JAPAN					
<i>PS</i>		63-102326	05/88	JAPAN					

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	<i>R. J. R. R.</i>	DATE CONSIDERED	9/3/04
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	APPLICANT	MAMITSU et al.	
	FILING DATE	Nov. 04, 2003	GROUP

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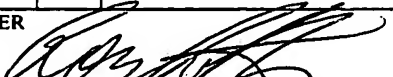
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
RP	5,990,550	Nov. 23, 1999	Umezawa		
RP	5,608,610	Mar. 4, 1997	Brzezinski		
RP	5,396,403	Mar. 7, 1995	Patel		
RP	5,293,301	Mar. 8, 1994	Tanaka et al.		
RP	5,641,997	June 24, 1997	Ohta et al.		
RP	5,789,820	Aug. 4, 1998	Yamashita		

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	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
RP	60-235430	11/85	JAPAN					
RP	07-240432	9/95	JAPAN					
RP	8-45874	2/96	JAPAN					
RP	60-95947	05/85	JAPAN					
RP	61-265849	11/86	JAPAN					
RP	62-141751	06/87	JAPAN					
RP	63-096946	04/88	JAPAN					
RP	62-92349	4/87	JAPAN					
RP	62-287649	12/87	JAPAN					
RP	59-38734	09/84	JAPAN					
RP	01-228138	09/89	JAPAN					
RP	54-40569	03/79	JAPAN					
RP	61-251043	11/86	JAPAN					
RP	54-95183	07/79	JAPAN					

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER		DATE CONSIDERED 9/3/04

FORM PTO-1449	ATTY. DKT NO.	1-103-CONS	SER. NO.
	APPLICANT	MAMITSU et al.	
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U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>RP</i>	2002/0158333	Oct. 31, 2002	Teshima		
<i>RP</i>	S/N 10/201556	July 24, 2002	Hirano et al.		
<i>RP</i>	5726466	March 10, 1998	Nishitani		
<i>RP</i>	4,470,063	Sep. 4, 1984	Arakawa et al.		
<i>RP</i>	5,708,299	Jan. 13, 1998	Teramae et al		

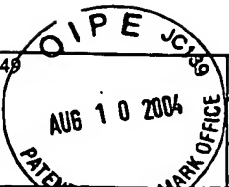
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	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
<i>RP</i>	59-031042	02/84	JAPAN					
<i>RP</i>	07-038013	02/95	JAPAN					
<i>RP</i>	07-273276	10/95	JAPAN					
<i>RP</i>	08-191145	07/96	JAPAN					
<i>RP</i>	2000-91485	03/00	JAPAN					
<i>RP</i>	W098/12748	3/26/98	PCT					
<i>RP</i>	JP-A-5-283562 *	10/29/93	JAPAN				X	
<i>RP</i>	JP-A-6-349987 *	12/22/94	JAPAN				X	
<i>RP</i>	JP-A-7-45765 *	2/14/95	JAPAN				X	
<i>RP</i>	JP-A-11-186469 *	7/9/99	JAPAN				X	
<i>RP</i>	JP-A-2000-31351 *	1/28/00	JAPAN				X	
<i>RP</i>	JP-A-2001-118961 *	4/27/01	JAPAN				X	

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	<i>[Signature]</i>	DATE CONSIDERED 9/3/04

FORM PTO-1448		ATTY. DKT NO. 01-103-CONS	SER. NO. 10/699,785
		APPLICANT MAMITSU et al.	
		FILING DATE November 4, 2003	GROUP 2811

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

FOREIGN PATENT DOCUMENTS

								TRANSLATION	
		DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
<i>PS</i>		JP-A-10-125700	05/15/98	JAPAN				Engl. Abstract	
<i>PS</i>		JP-A-61-147539	07/05/86	JAPAN				Engl. Abstract	

* Full English text of the JP Document will be available in machine-translated form from JP (Japanese Patent Office) English language web site at <http://www1.ipdl.jpo.go.jp/PA1/cgi-bin/PA1INDEX>.

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER <i>[Signature]</i>	DATE CONSIDERED <i>9/3/04</i>